Linear IC Converter CMOS A/D Converter (With 4-channel Input at 12-bit Resolution)

MB88101A

DESCRIPTION

The MB88101A is an analog-to-digital converter that converts its analog input to a 12-bit digital value and outputs it as serial data.

The MB88101A employs a successive approximation method for A/D conversion.

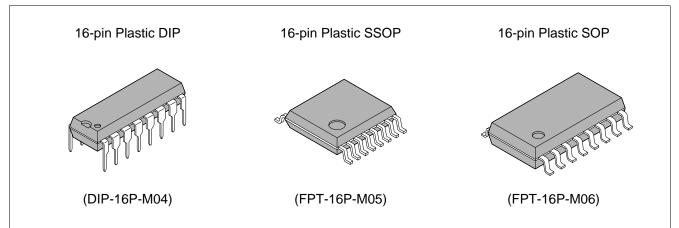
The MB88101A has four input channels selectable for analog input under control of the dedicated external pins.

The MB88101A can be switched to a mode for continuous A/D conversion, in which it outputs serial data from the MSB or LSB selectable depending on the mode setting.

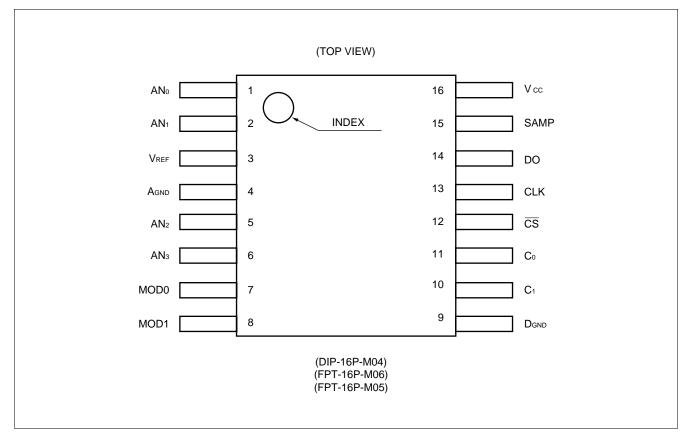
FEATURES

- 4-channel analog input
- One analog input channel selectable for conversion by external control
- · CR-type successive approximation system with a sample-and-hole circuit
- 12-bit resolution
- Serial output of 12-bit digital data
- Capable of continuous conversion (continuous conversion mode)
- · MSB or LSB selectable for serial output
- CMOS process
- Package options of 16-pin DIP, SSOP, and SOP available

PACKAGES



■ PIN ASSIGNMENT



2

■ PIN DESCRIPTION

Pin no.	Symbol	I/O	Descriptions
1 2 5 6	AN0 AN1 AN2 AN3	I	Analog input pins. One of these channels can be selected depending on the C_0 and C_1 settings.
14	DO	0	This pin outputs the result of A/D conversion. The result is 12-bit serial data output in synchronization with the rise of CLK.
13	CLK	I	Clock input pin for A/D conversion
12	CS	I	Chip select signal input pin. Setting the signal level to "L" after turning the power on starts A/D conversion; setting it to "H" stops A/D conversion. When this pin is "H", the DO and SAMP pins are "Hi-z".
11 10	C ₀ C ₁	I	Input pins for selecting the analog input channels from among pins AN_0 to AN_3 . See Table 1 for the correspondence between the pin settings and the channels selected. To switch the channel in mode 2 or 3, set these pins before the SAMP pin goes "H".
7 8	MOD0 MOD1	Ι	Conversion mode setting pins. For the correspondence between the pin settings and the modes selected, see Table 2 and "■ FUNCTIONAL DESCRIPTION."
15	SAMP	0	This pin becomes active in prior to data output. Serial data is output from the DO pin three clock cycles after the signal level at this pin goes "L" after "H" for one clock cycle.
3	Vref	—	Reference voltage input pin
4	Agnd	—	Analog circuit ground pin
9	Dgnd	—	Digital circuit ground pin
16	Vcc	—	Power supply pin

Channel selection

Table 1 Pin Settings and Channel Selection

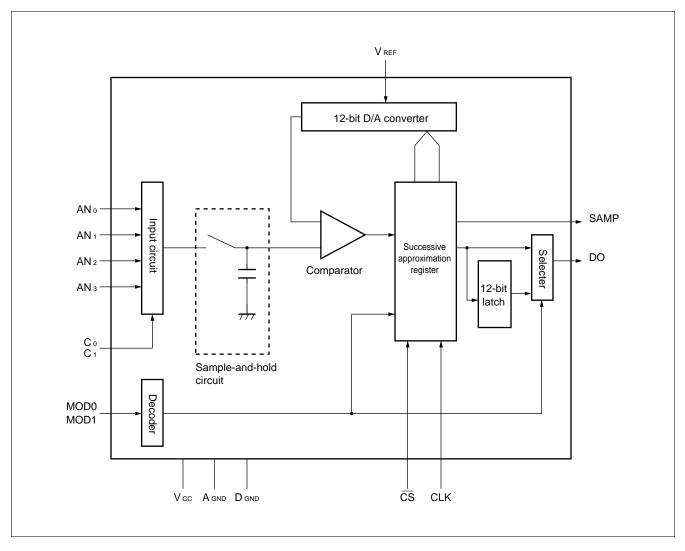
C 1	Co	Channel
L	L	ANo
L	Н	AN ₁
Н	L	AN ₂
Н	Н	AN ₃

Mode selection

Table 2 Pin Settings and Mode Selection

MOD 0	MOD1	Mode
L	L	Mode 1
L	Н	Mode 2
Н	L	(Disabled)
Н	Н	Mode 3

BLOCK DIAGRAM

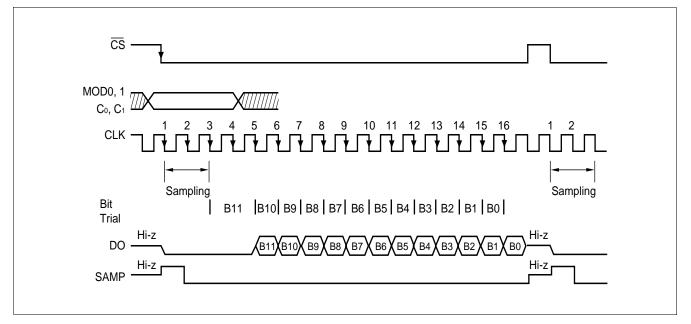


■ FUNCTIONAL DESCRIPTION

1. Mode 1

This mode sets the DO pin to "L" and stops conversion upon completion of conversion of 12 bits. To restart conversion, set \overline{CS} to "H" once then to "L". In this mode, converted data is output from the MSB.

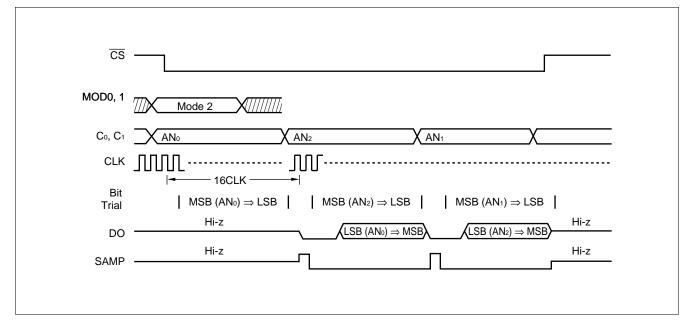
• Timing diagram



2. Mode 2

This mode continues conversion until \overline{CS} becomes "H" after it becomes "L". Converted data is output from the LSB, with the first piece of converted data output 20 clock cycles after \overline{CS} becomes "L". Changing the channel select pin settings before starting sampling of one analog input allows another to be converted.

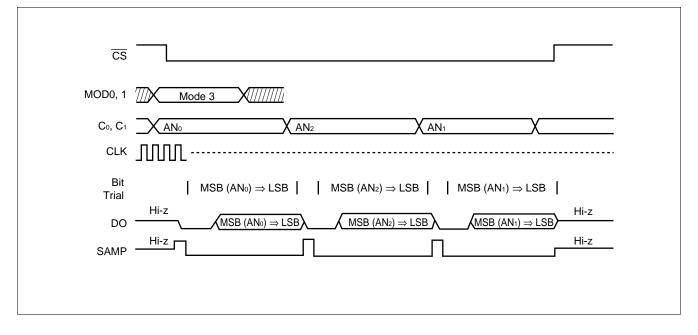
• Timing diagram



3. Mode 3

This mode continues conversion until \overline{CS} becomes "H" after it becomes "L". Converted data is output from the MSB. Changing the channel select pin settings before starting sampling of one analog input allows another to be converted.

• Timing diagram



ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Conditions	Rat	Unit	
Falameter	Symbol	Symbol		Max.	Unit
Power supply veltage	Vcc		-0.3	+7.0	V
Power supply voltage	Vref	Based on GND	-0.3*	+7.0*	V
Input voltage	Vin	(Ta = +25°C)	-0.3	Vcc + 0.3	V
Output voltage	Vout		-0.3	Vcc + 0.3	V
Power consumption	PD	—		150	mW
Operating temperature	Та	_	-20	+85	°C
Storage temperature	Tstg	_	-55	+150	°C

* : Vcc \geq Vref

WARNING: Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of absolute maximum ratings. Do not exceed these ratings.

RECOMMENDED OPERATING CONDITIONS

Parameter	Symbol	Value			
Falanietei	Symbol	Min.	Тур.	Max.	Unit
Dowor oupply voltage	Vcc	3.3	—	5.5	V
Power supply voltage	GND	—	0		V
Operation temperature	Та	-20		+85	°C

WARNING: Recommended operating conditions are normal operating ranges for the semiconductor device. All the device's electrical characteristics are warranted when operated within these ranges.

Always use semiconductor devices within the recommended operating conditions. Operation outside these ranges may adversely affect reliability and could result in device failure.

No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their FUJITSU representative beforehand.

■ ELECTRICAL CHARACTERISTIC

1. DC Characteristics

(1) Digital section

Deremeter	Symbol	Din nome	Conditiono	Value			Unit
Parameter	Symbol	Pin name	Conditions	Min.	Тур.	Max.	Onit
Power supply voltage	Vcc			3.3	5.0	5.5	V
Power supply current	lcc	Vcc	Operation at CLK =166kHz (with no load)	_	0.8	2.0	mA
Input leakage current	IILK	MOD0, 1 CLK CS	V _{IN} = 0 to V _{CC}	-10	—	10	μA
Low-level input voltage	VIL		_	V _{SS} - 0.3	_	0.2 Vcc	V
High-level input voltage	Vih	C ₀ C ₁	_	0.8 Vcc	_	Vcc+ 0.3	V
High-impedance output leakage current	lolz		VIN = 0 to Vcc	-10	_	10	μA
Low-level output voltage	Vol	DO SAMP	lo∟ = 2.5 mA	—	_	0.4	V
High-level output voltage	Vон		Іон = -400 μА	Vcc- 0.4	_	_	V

(Vcc = 3.3 V to 5.5 V, D_{GND} = 0 V, Ta = -20° C to $+85^{\circ}$ C)

(2) Analog section

(VREF, VCC = 3.3 V to 5.5 V (VCC \ge VREF), Agnd = 0 V, Ta = -20°C to +85°C)

Parameter	Symbol	Pin name	Value			Unit
Farameter	Symbol	Fin name	Min.	Тур.	Max.	Unit
Resolution	—		—	12	—	bits
Linearity error	—	AN₀ to AN₃	-4.0		2.0	LSB
Differential linearity error	—		-1.0		3.0	LSB
Conversion time	_	—		16	_	CLK
Consumption current	IREF	Vref	_	100	300	μΑ
Analog reference voltage	—	VREF	3.3	5.0	Vcc	V
Analog input voltage		AN ₀ to AN ₃	0		Vref	V

(3) Definitions of A/D converter terms

Resolution

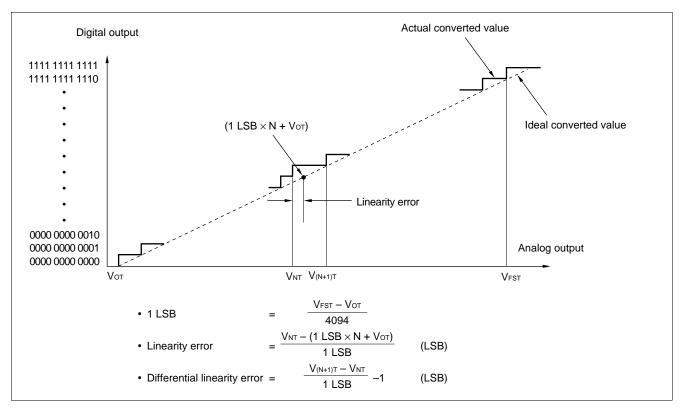
Analog transition identifiable by the A/D converter

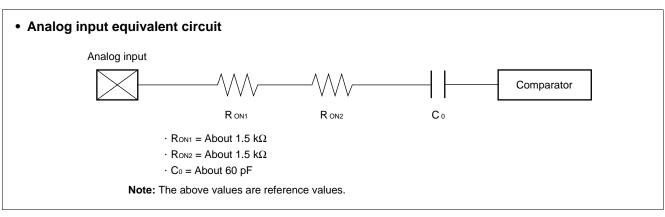
• Linearity error

Deviation of the straight line drawn between the zero transition point (0000 0000 \leftrightarrow 0000 0000 0001) and the full-scale transition point (1111 1111 1110 \leftrightarrow 1111 1111 1111) of the device from actual conversion characteristics

Differential linearity error

Deviation from the ideal input voltage required to shift output code by one LSB





- Notes: The tolerance of output impedance of an external circuit connected to this A/D converter has an effect on conversion time (CLK frequency). See "■ TYPICAL CHARACTERISTICS".
 - If the output impedance of the external input is too high, the analog voltage sampling time may be short.
 - When turning the device on, turn the power supply for the digital system first before turning VREF on.

2. AC Characteristics

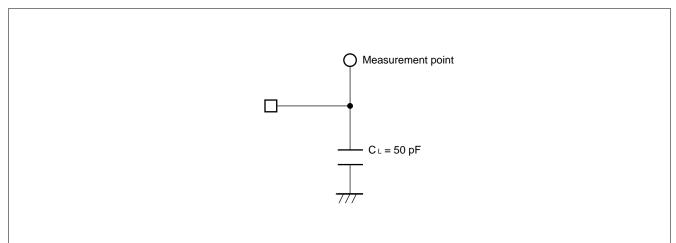
(V	REF, VCC = 3.3	V to +5.5 V (Vcc ≥ Vref)	1		, to +85°C)
Parameter	Symbol	Conditions	Value		Unit
Farameter	Symbol	Conditions	Min.	Max.	Onit
Clock cycle time	tour	Vcc = 5 V ± 10% *1	1.0	30.0	μs
	tclk	—	6.0	30.0	μs
Low-level clock pulse width	tcĸ∟	_	2.8	14.8	μs
High-level clock pulse width	tскн	_	2.8	14.8	μs
Clock rise time Clock fall time	tcr tc r	_	—	0.2	μs
CS setup time	tcss	—	tск∟ + 0.4	—	μs
CS hold time	tсsн	—	1.0	—	μs
CS release time	t csr	—	1.0	—	CLK
Channel setup time	tснs	—	0	—	μs
Channel hold time	tснн	_	1.0	—	CLK
Data output delay time	too	*2	—	0.5	μs
MOD setup time	tмos	—	0.2	—	μs
MOD hold time	tмон	—	0.1	—	μs
Data active delay time	t dve	—	_	0.5	μs
Data float delay time	t dze	—	—	0.5	μs
SAMP active delay time	t sve	_	_	0.5	μs
SAMP float delay time	tsze	—		0.5	μs
SAMP high-level output delay time	t shd	*2	—	0.5	μs
SAMP low-level output delay time	tsld	*2		0.5	μs

$(V_{REF}, V_{CC} = 3.3 \text{ V to } +5.5 \text{ V} (V_{CC} \ge V_{REF}), A_{GND} = 0 \text{ V}, \text{ Ta} = -20^{\circ}\text{C to } +85^{\circ}\text{C})$

*1: Depending on the output impedance of the external circuit connected to the analog input pin

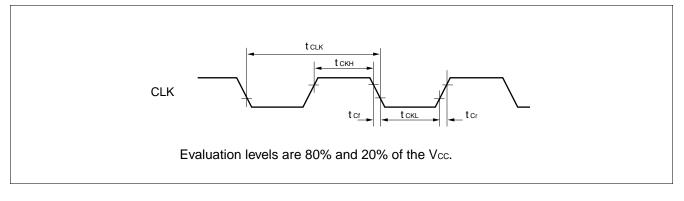
*2: See "• AC test circuit."

• AC test circuit

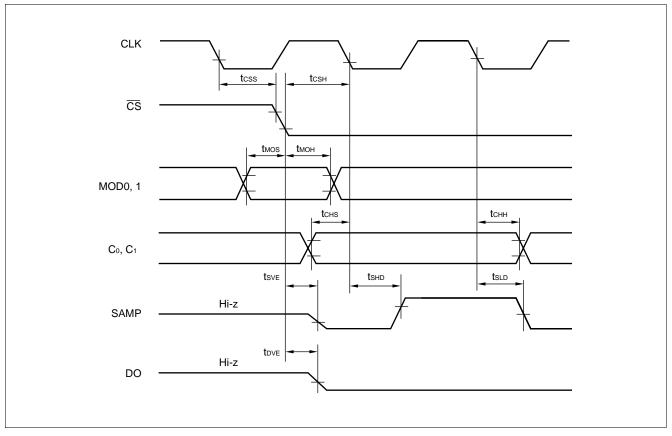


■ TIMING DIAGRAM

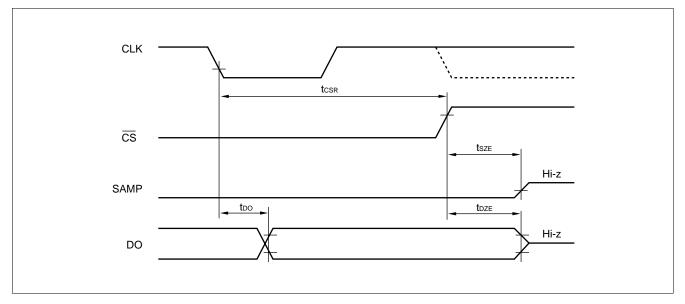
(1) Input clock timing



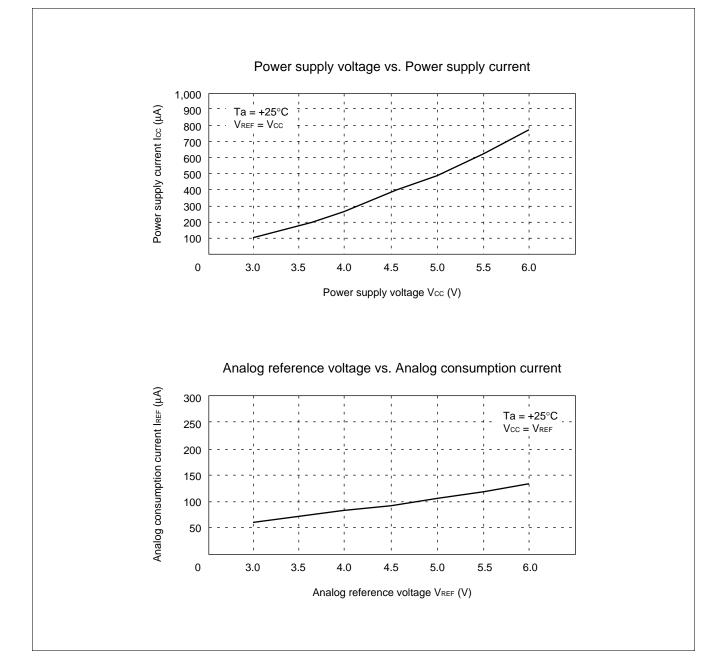
(2) A/D startup timing

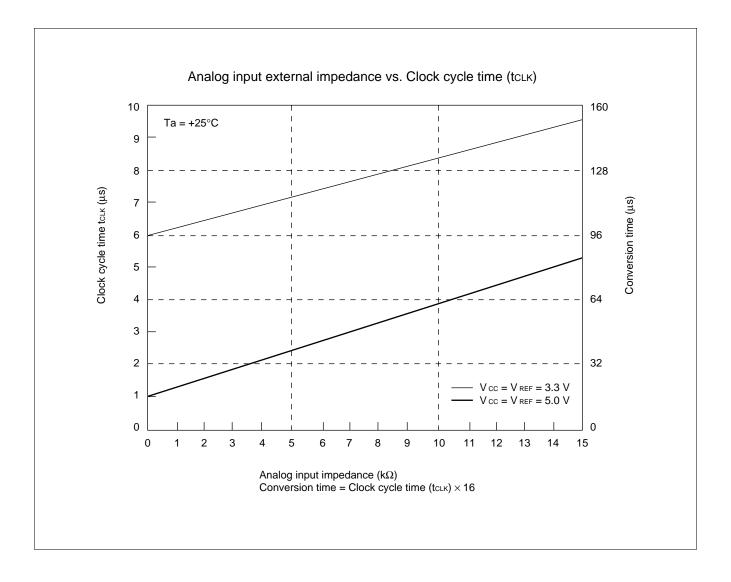


(3) Data output delay time and A/D stop timing



■ TYPICAL CHARACTERISTICS

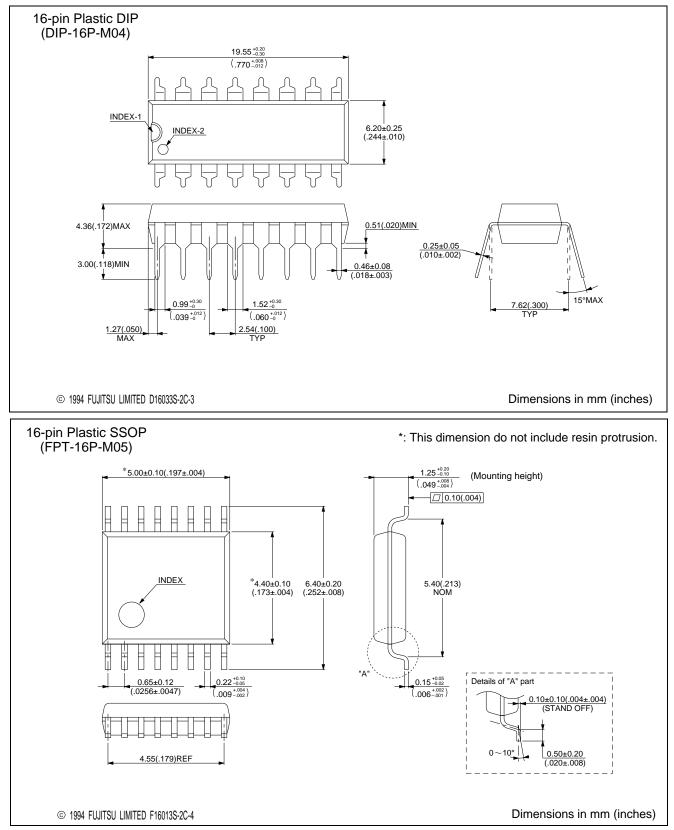


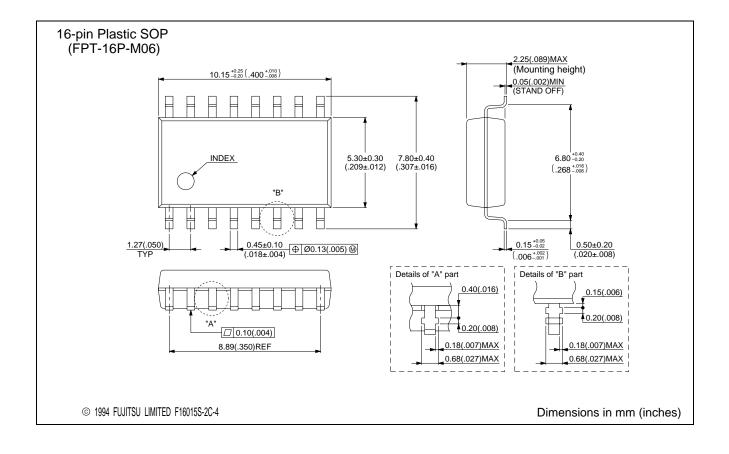


■ ORDERING INFORMATION

Part number	Package	Remarks
MB88101AP	16-pin Plastic DIP (DIP-16P-M04)	
MB88101APFV	16-pin Plastic SSOP (FPT-16P-M05)	
MB88101APF	16-pin Plastic SOP (FPT-16P-M06)	

■ PACKAGE DIMENSIONS





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